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Applicant(s)/Patent under Reexamination

HAYASHI ET AL.

10/500,873

Examiner

Art Unit

Andre J. Allen

2855

	SEARCHED				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEAR)
	DATE	EXMR
Prior search updated	11/27/2006	AA
inventor name searched	11/27/2006	АА
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